

**On Goodness-of-Fit Testing for Continuous Time
Stochastic Processes
(Poisson and Diffusion)**

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Poisson Processes

We observe a periodic Poisson process $X^T = \{X_t, 0 \leq t \leq T\}$ of intensity function $\lambda(\cdot)$ and consider the following hypotheses testing problem:

$$\mathcal{H}_0 \quad : \quad \lambda(t) \equiv \lambda_*(t), \quad t \geq 0$$

where $\lambda_*(t)$ is known periodic function of period τ , against

$$\mathcal{H}_1 \quad : \quad \lambda(t) \neq \lambda_*(t), \quad t \geq 0,$$

but $\lambda(t)$ is always τ -periodic. Let us suppose that $T = n\tau$ and denote $X_j(t) = X_{\tau(j-1)+t} - X_{\tau(j-1)}$, $j = 1, \dots, n$. Put

$$\hat{\Lambda}_n(t) = \frac{1}{n} \sum_{j=1}^n X_j(t) \rightarrow \Lambda(t) = \int_0^t \lambda(s) ds.$$

The GoF tests of C-vM and K-S type can be based on the statistics

$$W_n^2 = \Lambda_*(\tau)^{-2} n \int_0^\tau \left[\hat{\Lambda}_n(t) - \Lambda_*(t) \right]^2 d\Lambda_*(t),$$

$$D_n = \Lambda_*(\tau)^{-1/2} \sup_{0 \leq t \leq \tau} \sqrt{n} \left| \hat{\Lambda}_n(t) - \Lambda_*(t) \right|.$$

It can be shown that

$$W_n^2 \implies \int_0^1 W(s)^2 ds, \quad D_n \implies \sup_{0 \leq s \leq 1} |W(s)|$$

where $W(\cdot)$ is a Wiener process. Hence these statistics are asymptotically distribution-free and the tests

$$\psi_n(X^T) = 1_{\{W_n^2 > c_\alpha\}} \in \mathcal{K}_\alpha, \quad \phi_n(X^T) = 1_{\{D_n > d_\alpha\}} \in \mathcal{K}_\alpha$$

where \mathcal{K}_α is the class of tests of asymptotic size α .

These tests are uniformly consistent against any alternative of the type

$$\mathcal{H}_\rho = \{\Lambda(\cdot) : \|\Lambda(\cdot) - \Lambda_*(\cdot)\| \geq \rho\}$$

but are not consistent against

$$\hat{\mathcal{H}}_\rho = \{\Lambda(\cdot) : \|\lambda(\cdot) - \lambda_*(\cdot)\| \geq \rho\}$$

because they *can not* see the intensities like

$$\lambda_k(t) = \lambda_*(t) + c_\rho \cos(kt), \quad k = 1, 2; \dots$$

For example, for the power function $\beta(\bar{\psi}, \lambda) = \mathbf{E}_\lambda \bar{\psi}$ we have

$$\inf_{\lambda(\cdot) \in \hat{\mathcal{H}}_\rho} \beta(\bar{\psi}, \lambda) \leq \inf_k \beta(\bar{\psi}, \lambda_k) \rightarrow \alpha$$

Let us consider the problem of testing alternatives like \mathcal{H}_ρ even with $\rho = \rho_T \rightarrow 0$, but we suppose that the functions $\lambda(\cdot)$ are sufficiently smooth. The intensity $\lambda_*(\cdot)$ we transform to constant using the time change

$$t = \int_0^s \lambda_*(v) dv, \quad 0 \leq t \leq T^* = \int_0^T \lambda_*(v) dv$$

and put $\tau = 1$. Hence

$$\mathcal{H}_0 \quad : \quad \lambda(t) = 1.$$

The alternative is

$$\mathcal{H}_1 \quad : \quad \lambda(\cdot) \in \Lambda_T = \left\{ \lambda(\cdot) : \|\lambda(\cdot) - 1\| \geq \rho_T, \left\| \lambda^{(\sigma)}(\cdot) \right\| \leq R \right\}.$$

Let us put $\lambda(t) = 1 + \vartheta(t)$ and introduce the trigonometric orthonormal base $\{\varphi_i(\cdot), i \in \mathbb{Z}\}$ in the space $\mathcal{L}_2(0, 1)$ as

$$\varphi_0(1) = 1, \quad \varphi_i(t) = \sqrt{2} \cos(2\pi it), \quad \varphi_{-i}(t) = \sqrt{2} \sin(2\pi it),$$

where $i > 0$. Then

$$\vartheta(t) = \sum_{i \in \mathbb{Z}} \vartheta_i \varphi_i(t), \quad \vartheta_i = \int_0^1 \vartheta(t) \varphi_i(t) dt$$

and Λ_T corresponds to Θ_T (with condition $\inf_t \vartheta(t) \geq -1$)

$$\Theta_T = \left\{ \vartheta : \sum_{i \in \mathbb{Z}} \vartheta_i^2 \geq \rho_T^2, \quad \sum_{i \in \mathbb{Z}} (2\pi |i|)^{2\sigma} \vartheta_i^2 \leq R^2 \right\}.$$

Our goal is to minimize the second type error $\gamma(\bar{\psi}, \vartheta) = 1 - \mathbf{E}_{\vartheta} \bar{\psi}$ uniformly on alternative:

$$\sup_{\vartheta \in \Theta_T} \gamma(\hat{\psi}, \vartheta) = \inf_{\bar{\psi} \in \mathcal{K}_\alpha} \sup_{\vartheta \in \Theta_T} \gamma(\bar{\psi}, \vartheta) + o(1).$$

The test $\hat{\psi} \in \mathcal{K}_\alpha$ we call asymptotically minimax.

Let us introduce the statistic

$$t_w = \sum_{i=-m}^m w_i (X_i^2 - 1),$$

where

$$w_i = z^2 \left(1 - \left| \frac{i}{m} \right|^{2\sigma} \right), \quad z = \left(2 \sum_{i=-m}^m \left[1 - \left| \frac{i}{m} \right|^{2\sigma} \right]^2 \right)^{-1/4},$$

and

$$X_i = \frac{1}{\sqrt{T}} \int_0^T \phi_i(t) [dX_t - dt].$$

Here $\phi_i(\cdot)$ is periodic prolongation of $\varphi_i(\cdot)$ on R_+ and

$$m = \left(\frac{R^2 c_1(\sigma)}{c_2(\sigma)} \right)^{\frac{1}{2\sigma}} \rho_T^{-\frac{1}{\sigma}} \longrightarrow \infty$$

Theorem 1. (*Ingster, Kutoyants*) *Let $\sigma > 1/4$, then the test*

$$\hat{\psi} = 1_{\{t_w > z_\alpha\}} \in \mathcal{K}_\alpha$$

is asymptotically minimax. Its power function admits the representations

$$\inf_{\vartheta \in \Theta_T} \beta(\hat{\psi}, \vartheta) = \mathbf{P}\{\zeta > z_\alpha - u_T\} + o(1)$$

where $\zeta \sim \mathcal{N}(0, 1)$ and

$$u_T = d(\sigma, R) T \rho_T^{\frac{4\sigma+1}{2\sigma}} (1 + o(1)).$$

The constants

$$c_1(\sigma) = \frac{4\sigma}{2\sigma + 1}, \quad c_2(\sigma) = \frac{2^{2\sigma+2} \pi^{2\sigma} \sigma}{(2\sigma + 1)(4\sigma + 1)},$$
$$c_3(\sigma) = \frac{8\sigma^2}{(2\sigma + 1)(4\sigma + 1)}$$

and

$$u_T \sim d(\sigma, R) T r_T^{2+\frac{1}{2\sigma}}, \quad d(\sigma, R) = \frac{c_3(\sigma)^{1/2} c_2(\sigma)^{1/\sigma}}{c_1(\sigma) R^{1/2\sigma}}.$$

The most interesting case is $u_T \rightarrow 1$. Then the separation rate

$$\rho_T = (d(\sigma, R) T)^{-\frac{2\sigma}{4\sigma+1}}$$

To prove this theorem we need to prove two different type results. The first one is to establish the lower bound on the errors: for all tests $\bar{\psi} \in \mathcal{K}_\alpha$

$$\sup_{\vartheta \in \Theta_T} \gamma(\bar{\psi}, \vartheta) \geq 1 - \Phi(z_\alpha - u_T) + o(1),$$

and the second is to show that for the test $\hat{\psi}$ we have the asymptotic equalities

$$\sup_{\vartheta \in \Theta_T} \gamma(\hat{\psi}, \vartheta) = 1 - \Phi(z_\alpha - u_T) + o(1),$$

Diffusion Processes

Let $X^T = \{X_t, 0 \leq t \leq T\}$ be an observation of solution of some SDE and we would like to know if this SDE is of the following form

$$dX_t = S_*(X_t) dt + \sigma(X_t) dW_t, \quad X_0, \quad 0 \leq t \leq T,$$

where the trend $S_*(\cdot)$ and diffusion coefficient $\sigma(\cdot)^2$ are known functions. Our goal is to construct a test (called *Goodness-of-Fit*) which can answer to this question. We study such tests in two types of asymptotics: *small noise* ($\sigma \rightarrow 0$) and *large samples* ($T \rightarrow \infty$).

Small Noise Asymptotics

Suppose that the observed process $X^\varepsilon = \{X_t, 0 \leq t \leq T\}$ is solution of the SDE

$$dX_t = S(X_t) dt + \varepsilon \sigma(X_t) dW_t, \quad X_0 = x_0, \quad 0 \leq t \leq T.$$

If $\varepsilon \rightarrow 0$ then the stochastic process X^ε converges to the deterministic function $\{x_t, 0 \leq t \leq T\}$, solution of the ordinary DE

$$\frac{dx_t}{dt} = S(x_t), \quad x_0, \quad 0 \leq t \leq T.$$

Our goal is to construct the GoF tests (C-vM and K-S type) for this model.

The basic hypothesis is simple:

$$\mathcal{H}_0 \quad : \quad x_t = x_t^*, \quad 0 \leq t \leq T, \quad \frac{dx_t^*}{dt} = S_*(x_t^*)$$

and the alternative is

$$\mathcal{H}_1 \quad : \quad \{S(\cdot) : \|x_t - x_t^*\| \geq \rho\}, \quad \rho > 0$$

Here x_t^* is solution x_t under hypothesis \mathcal{H}_0 . Introduce two statistics

$$W_\varepsilon^2 = \int_0^T \left(\frac{X_t - x_t^*}{\tau \varepsilon S_*(x_t^*)} \right)^2 \sigma(x_t^*)^2 dt, \quad \tau = \tau(T)$$

$$D_\varepsilon = \sup_{0 \leq t \leq T} \left| \frac{X_t - x_t^*}{\sqrt{\tau} \varepsilon S_*(x_t^*)} \right|, \quad \tau(s) = \int_0^s \left(\frac{\sigma(x_t^*)}{S_*(x_t^*)} \right)^2 dt$$

The *C-vM* and *K-S* type tests

$$\psi_\varepsilon (X^\varepsilon) = 1_{\{W_\varepsilon^2 > c_\alpha\}} \in \mathcal{K}_\alpha, \quad \phi_\varepsilon (X^\varepsilon) = 1_{\{D_\varepsilon > d_\alpha\}} \in \mathcal{K}_\alpha$$

with the constants c_α, d_α defined by the equations

$$\mathbf{P} \left\{ \int_0^1 W(s)^2 ds > c_\alpha \right\} = \alpha, \quad \mathbf{P} \left\{ \sup_{0 \leq s \leq 1} |W(s)| > d_\alpha \right\} = \alpha,$$

where $W(\cdot)$ is standard Wiener process. The both tests are *distribution free* and uniformly consistent against any alternative \mathcal{H}_ρ .

Let us consider local (contiguous) alternatives of the following form

$$dX_t = S_*(X_t) dt + \varepsilon \frac{h(X_t) \sigma(X_t)^2}{\sqrt{\tau} S_*(X_t)} dt + \varepsilon dW_t, \quad 0 \leq t \leq T.$$

and denote $h_*(v) = h(x_{s(vu_T)})$, $0 \leq v \leq 1$, where $s(\tau)$ is inverse to $\tau(s)$. We have the convergence

$$W_\varepsilon^2 \implies \int_0^1 \left[W(s) + \int_0^s h_*(v) dv \right]^2 ds,$$

$$D_\varepsilon \implies \sup_{0 \leq s \leq 1} \left| W(s) + \int_0^s h_*(v) dv \right|$$

The power function

$$\beta(\psi_\varepsilon, h) \rightarrow \mathbf{P} \left\{ \int_0^1 \left[W(s) + \int_0^s h_*(v) dv \right]^2 ds > c_\alpha \right\}$$

Note that these tests are not uniformly consistent against alternatives of the form

$$\mathcal{H}_\rho^* : \{S(\cdot) : \|S(\cdot) - S_*(\cdot)\| \geq \rho\}, \quad \rho > 0$$

because for the functions like $S_k(x) = S_*(x) + h_k(x)$

$$h_k(x) = c_\rho \cos(k(x - x_0)), \quad k = 1, 2, \dots$$

we have

$$\inf_{S(\cdot) \in \mathcal{H}_\rho} \beta(\psi_\varepsilon, h) \leq \inf_k \beta(\psi_\varepsilon, h_k) \rightarrow \alpha$$

Chi Square Test

The basic hypothesis as before is simple

$$dX_t = S_*(X_t) dt + \varepsilon \sigma(X_t) dW_t, \quad X_0 = x_0, \quad 0 \leq t \leq T,$$

and the alternative we write as

$$dX_t = S_*(X_t) dt + h(X_t) \sigma(X_t) \sqrt{|S_*(X_t)|} dt + \varepsilon \sigma(X_t) dW_t, \quad X_0 = x_0,$$

where

$$h(x) = (x_T^* - x_0)^{-1/2} h_* \left(\frac{x - x_0}{x_T^* - x_0} \right), \quad \frac{dx_t^*}{dt} = S_*(x_t^*), \quad x_0^* = x_0.$$

Therefore, the alternative is entirely defined by the function $h_*(\cdot)$.

We suppose that $h_*(\cdot) \in \mathbb{H}_r$:

$$\mathbb{H}_r = \left\{ h(\cdot) : \|h(\cdot)\| \geq r_\varepsilon, \quad \left\| h^{(k)}(\cdot) \right\| \leq R \right\},$$

where $\|\cdot\|$ is $\mathcal{L}_2(0,1)$ -norm and $r = r(\varepsilon) \rightarrow 0$. We call a test $\hat{\psi}_\varepsilon$ asymptotically minimax in \mathcal{K}_α if

$$\sup_{h_* \in \mathbb{H}_r} \gamma(\hat{\psi}_\varepsilon, h_*) = \inf_{\bar{\psi}_\varepsilon \in \mathcal{K}_\alpha} \sup_{h_* \in \mathbb{H}_r} \gamma(\bar{\psi}_\varepsilon, h_*) + o(1).$$

Here $\gamma(\bar{\psi}_\varepsilon, h_*) = 1 - \mathbf{E}_{h_*} \bar{\psi}_\varepsilon = 1 - \beta(\bar{\psi}_\varepsilon, h_*)$

Let us introduce orthonormal base in $\mathcal{L}_2(0, 1)$: $\varphi_0(y) = 1$,

$$\varphi_j(y) = \sqrt{2} \sin(2\pi jy), \quad j > 0, \quad \varphi_j(y) = \sqrt{2} \cos(2\pi jy), \quad j < 0$$

and write

$$h_*(y) = \sum_{j \in \mathbb{Z}} \vartheta_j \varphi_j(y), \quad \vartheta_j = \int_0^1 h_*(y) \varphi_j(y) dy.$$

The set \mathbb{H}_r can be rewritten in terms of $\vartheta = \{\vartheta_j\}$ as follows

$$\Theta_r = \left\{ \vartheta : \sum_{j \in \mathbb{Z}} \vartheta_j^2 \geq r_\varepsilon^2, \quad \sum_{j \in \mathbb{Z}} (2\pi j)^{2k} \vartheta_j^2 \leq R^2 \right\}.$$

The Chi-square test we construct with the help of the random variables

$$X_j^\varepsilon = \int_0^T \varphi_j \left(\frac{X_t - x_0}{x_T^* - x_0} \right) \frac{\sqrt{|S_*(X_t)|}}{\sqrt{x_T^* - x_0} \sigma(X_t)} [dX_t - S_*(X_t) dt],$$

Let us put

$$q_w = \sum_{|j| \leq m} w_j \left[(X_j^\varepsilon)^2 - 1 \right], \quad m = \left(\frac{R^2 c_1(\sigma)}{c_2(\sigma)} \right)^{\frac{1}{2\sigma}} r_\varepsilon^{-\frac{1}{\sigma}} \longrightarrow \infty$$

where

$$w_j = z^2 \left(1 - \left| \frac{j}{m} \right|^{2\sigma} \right), \quad z = \left(2 \sum_{j=-m}^m \left[1 - \left| \frac{j}{m} \right|^{2\sigma} \right]^2 \right)^{-1/4},$$

Theorem 2. *Let $h_*(\cdot) \in \mathbb{H}_r$ with $k \geq 1$, then the test*

$$\hat{\psi} = 1_{\{q_w > z_\alpha\}} \in \mathcal{K}_\alpha$$

and is asymptotically minimax. Its second type error admits the representations

$$\sup_{\vartheta \in \Theta_T} \gamma(\hat{\psi}, \vartheta) = 1 - \Phi(z_\alpha - u_\varepsilon) + o(1)$$

where

$$u_\varepsilon = d(\sigma, R) \varepsilon^{-1} r_\varepsilon^{\frac{4\sigma+1}{2\sigma}} (1 + o(1)).$$

The test statistic can be simplified as follows, let us put

$$Y_j^\varepsilon = \int_0^T \varphi_j \left(\frac{x_t^* - x_0}{x_T^* - x_0} \right) \frac{\sqrt{|S_*(x_t^*)|}}{\sqrt{x_T^* - x_0} \sigma(X_t)} [dX_t - S_*(X_t) dt],$$

and note that under hypothesis the random variables Y_j^ε are independent and $Y_j^\varepsilon \sim \mathcal{N}(0, 1)$. The test statistic is

$$Q_w = \sum_{|j| \leq m} w_j \left[(Y_j^\varepsilon)^2 - 1 \right],$$

where w_j and m are the same as before. Then the test

$$\tilde{\psi} = 1_{\{Q_w > z_\alpha\}} \in \mathcal{K}_\alpha$$

has the same asymptotic properties as $\hat{\psi}$ above.

Ergodic Diffusion

Suppose that the observed process is one dimensional ergodic diffusion

$$dX_t = S(X_t) dt + \sigma(X_t) dW_t, \quad X_0, \quad 0 \leq t \leq T,$$

i.e., there exists an invariant probability distribution $f_S(x)$ such that

$$\frac{1}{T} \int_0^T g(X_t) dt \longrightarrow \int_{-\infty}^{\infty} g(x) f_S(x) dx = \mathbf{E}_S g(\xi).$$

where

$$f_S(x) = \frac{1}{G(S) \sigma(x)^2} \exp \left\{ 2 \int_0^x \frac{S(y)}{\sigma(y)^2} dy \right\}.$$

The basic hypothesis \mathcal{H}_0 is simple: $S(x) = S_*(x)$.

We propose two different type of tests. The **First** one is based on the following two statistics

$$W_T^2 = \frac{1}{T^2 \mathbf{E}_{S_*} [\sigma(\xi)^2]} \int_0^T \left[X_t - X_0 - \int_0^t S_*(X_v) dv \right]^2 dt,$$

$$D_T = \frac{1}{\sqrt{T \mathbf{E}_{S_*} [\sigma(\xi)^2]}} \sup_{0 \leq t \leq T} \left| X_t - X_0 - \int_0^t S_*(X_v) dv \right|$$

It can be shown that under hypothesis \mathcal{H}_0

$$W_T^2 \implies \int_0^1 W(s)^2 ds, \quad D_T \implies \sup_{0 \leq s \leq 1} |W(s)|.$$

Hence the C-vM and K-S type tests

$$\psi_T (X^T) = 1_{\{W_T^2 > c_\alpha\}} \in \mathcal{K}_\alpha, \quad \phi_T (X^T) = 1_{\{D_T > d_\alpha\}} \in \mathcal{K}_\alpha$$

with the same constants c_α and d_α .

Remind that $\mathbf{E}_{S_*} S_*(\xi) = 0$. These tests are consistent against any alternative of the type

$$\mathcal{H}_1 = \{S(\cdot) : \mathbf{E}_{S_*} S(\xi) \neq 0\}.$$

Let us denote

$$\mathcal{H}_\rho = \{h(\cdot) : \mathbf{E}_{S_*} h(\xi) \geq \rho\}$$

where $\rho > 0$.

The contiguous alternatives we introduce by the SDE

$$dX_t = S(X_t) dt + \frac{h(X_t)}{\sqrt{T}} dt + \sigma(X_t) dW_t, \quad X_0, \quad 0 \leq t \leq T.$$

We put $\rho_h = \mathbf{E}_{S_*} h(\xi) \left(\mathbf{E}_{S_*} \left[\sigma(\xi)^2 \right] \right)^{-1/2}$. The limits for the both statistics under alternative \mathcal{H}_ρ are

$$W_T^2 \Rightarrow \int_0^1 [W(s) + \rho_h s]^2 ds, \quad D_T \Rightarrow \sup_{0 \leq s \leq 1} |W(s) + \rho_h s|$$

We can compare these tests with the Neyman-Pearson test

$$\hat{\psi}_T(X^T, h) = 1_{\{Z_T(h) > c_\alpha(h)\}}$$

for simple alternatives. Here $Z_T(h)$ is the LR function.

Its power function ($\zeta \sim \mathcal{N}(0, 1)$)

$$\beta(\hat{\psi}_T, h) \rightarrow \mathbf{P} \left\{ \zeta > z_\alpha - \sqrt{I(h)} \right\}, \quad I(h) = \mathbf{E}_{S_*} \left(\frac{h(\xi)}{\sigma(\xi)} \right)^2$$

The least favorable alternative corresponds to

$$\inf_{h(\cdot) \in \mathcal{H}_\rho} I(h) = \rho_h^2, \quad \mathcal{H}_\rho = \{h(\cdot) : \mathbf{E}_{S_*} h(\xi) \geq \rho\}.$$

Hence

$$\inf_{h(\cdot) \in \mathcal{H}_\rho} \beta(\hat{\psi}_T, h) \rightarrow \mathbf{P} \{ \zeta > z_\alpha - \rho_h \},$$

Let us introduce statistic

$$V_T (X^T) = \left(T \mathbf{E}_{S_*} \left[\sigma (\xi)^2 \right] \right)^{-1/2} \left[X_T - X_0 - \int_0^T S_* (X_t) dt \right]$$

and the corresponding test

$$\tilde{\psi}_T (X^T) = 1_{\{V_T(X^T) > z_\alpha\}} \in \mathcal{K}_\alpha.$$

Then its power function

$$\beta \left(\tilde{\psi}_T, h \right) = \mathbf{E}_{S_h} \tilde{\psi}_T (X^T) \rightarrow \beta \left(\tilde{\psi}, h \right) = \mathbf{P} \{ \zeta > z_\alpha - \rho_h \}$$

and the least favorable means

$$\inf_{h(\cdot) \in \mathcal{H}_\rho} \beta \left(\tilde{\psi}, h \right) = \mathbf{P} \{ \zeta > z_\alpha - \rho_h \}$$

Hence this test is AUMP.

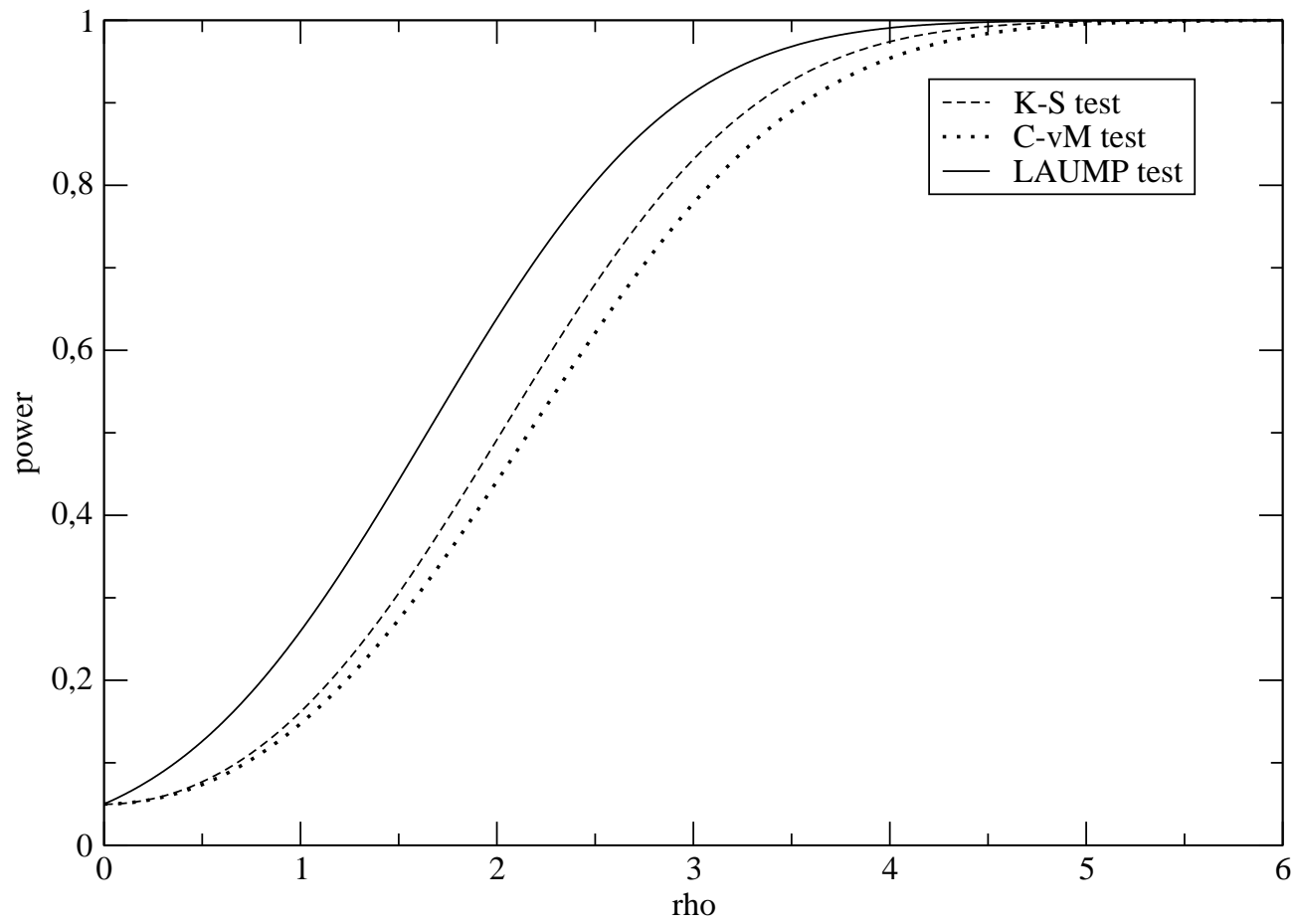
We can compare these three tests by their limit powers

$$(C - vM) \quad \beta(\psi, \rho) = \mathbf{P} \left\{ \int_0^1 [W(s) + \rho s]^2 ds > c_\alpha \right\},$$

$$(K - S) \quad \beta(\phi, \rho) = \mathbf{P} \left\{ \sup_{0 \leq s \leq 1} |W(s) + \rho s| > d_\alpha \right\},$$

$$(AUMP) \quad \beta(\tilde{\psi}, \rho) = \mathbf{P} \{ \zeta > z_\alpha - \rho \}$$

The results of simulation we find on the next slide.



The **Second** type of tests is a direct analogue of the classical Cramér-von Mises and Kolmogorov-Smirnov tests based on empirical distribution and density functions:

$$\hat{F}_T(x) = \frac{1}{T} \int_0^T 1_{\{X_t < x\}} dt, \quad \hat{f}_T(x) = \frac{2}{T} \int_0^T 1_{\{X_t < x\}} dX_t$$

Remind that both of them are unbiased:

$$\mathbf{E}_S \hat{F}_T(x) = F_S(x), \quad \mathbf{E}_S \hat{f}_T(x) = f_S(x),$$

admit the representations

$$\eta_T(x) = -\frac{2}{\sqrt{T}} \int_0^T \frac{F_S(X_t \wedge x) - F_S(X_t) F_S(x)}{f_S(X_t)} dW_t + o(1),$$

$$\zeta_T(x) = -\frac{2f_S(x)}{\sqrt{T}} \int_0^T \frac{1_{\{X_t > x\}} - F_S(X_t)}{f_S(X_t)} dW_t + o(1)$$

The Cramér-von Mises and Kolmogorov-Smirnov type test statistics are

$$W_T^2 = T \int_{-\infty}^{\infty} \left[\hat{F}_T(x) - F_{S_*}(x) \right]^2 dF_{S_*}(x),$$

$$D_T = \sup_x \sqrt{T} \left| \hat{F}_T(x) - F_{S_*}(x) \right|$$

and

$$v_T^2 = T \int_{-\infty}^{\infty} \left[\hat{f}_T(x) - f_{S_*}(x) \right]^2 dF_{S_*}(x),$$

$$d_T = \sup_x \sqrt{T} \left| \hat{f}_T(x) - f_{S_*}(x) \right|$$

respectively. Unfortunately, all these statistics are not distribution-free even asymptotically and the choice of the corresponding thresholds for the tests is much more complicate.

The Cramér-von Mises and Kolmogorov-Smirnov type tests based on these statistics are

$$\begin{aligned}\Psi_T (X^T) &= 1_{\{W_T^2 > C_\alpha\}}, & \Phi_T (X^T) &= 1_{\{D_T > D_\alpha\}}, \\ \psi_T (X^T) &= 1_{\{v_T^2 > c_\alpha\}}, & \phi_T (X^T) &= 1_{\{d_T > d_\alpha\}}\end{aligned}$$

with corresponding constants belong to $\in \mathcal{K}_\alpha$.

The contiguous alternatives can be introduced by the following way

$$S(x) = S_*(x) + \frac{h(x)}{\sqrt{T}}.$$

Then we obtain for the Cramér-von Mises statistics the limits

$$W_T^2 \Rightarrow \int \left[2\mathbf{E}_{S_*} \left(\left[1_{\{\xi < x\}} - F_{S_*}(x) \right] \int_0^\xi h(s) ds \right) + \eta(x) \right]^2 dF_{S_*}(x),$$

$$v_T^2 \Rightarrow \int \left[2\mathbf{E}_{S_*} \int_\xi^x h(s) ds + \zeta(x) \right]^2 dF_{S_*}(x).$$

where $\eta(\cdot)$ and $\zeta(\cdot)$ are limit gaussian processes:

$$\sqrt{T} \left(\hat{F}_T(x) - F_{S_*}(x) \right) \Rightarrow \eta(x), \quad \sqrt{T} \left(\hat{f}_T(x) - f_{S_*}(x) \right) \Rightarrow \zeta(x)$$

Partially Observed Processes

Let us consider the partially observed system

$$\begin{aligned}dY_t &= -a Y_t dt + b dV_t, & Y_0, \\dX_t &= c Y_t dt + \sigma dW_t, & X_0, \quad 0 \leq t \leq T\end{aligned}$$

where $a > 0, b > 0, c > 0$. We observe $X^T = \{X_t, 0 \leq t \leq T\}$ and we have to construct C-vM and K-S type tests to check if this model corresponds well to X^T . Remind that $m_t = \mathbf{E}_0(Y_t | X_s, 0 \leq s \leq t)$ satisfies the Kalman-Bucy equations:

$$\begin{aligned}dm_t &= c m_t dt + \frac{c \gamma_t}{\sigma^2} [dX_t - c m_t dt], & m_0 \\ \frac{d\gamma_t}{dt} &= -2a \gamma_t - \frac{c^2 \gamma_t^2}{\sigma^2} + b^2, & \gamma_0, \quad 0 \leq t \leq T\end{aligned}$$

Let us introduce the statistics

$$W_T^2 = \frac{1}{T^2 \sigma^2} \int_0^T \left[X_t - X_0 - c \int_0^t m_s ds \right]^2 dt,$$

$$D_T = \frac{1}{\sigma \sqrt{T}} \sup_{0 \leq t \leq T} \left| X_t - X_0 - c \int_0^t m_s ds \right|.$$

Then under hypothesis \mathcal{H}_0 we have

$$W_T^2 = \int_0^1 W(s)^2 ds, \quad D_T = \sup_{0 \leq s \leq 1} |W(s)|.$$

and the tests

$$\psi_T (X^T) = 1_{\{W_T^2 > c_\alpha\}}, \quad \phi_T (X^T) = 1_{\{D_T > d_\alpha\}}$$

with corresponding constants belong to $\in \mathcal{K}_\alpha$.

These tests are consistent against any alternative of the type

$$dY_t = -a Y_t dt + b dV_t, \quad Y_0,$$

$$dX_t = c Y_t dt + h(X_t) dt + \sigma dW_t, \quad X_0, \quad 0 \leq t \leq T.$$

The contiguous alternatives can be introduced by the equations

$$dY_t = -a Y_t dt + b dV_t, \quad Y_0,$$

$$dX_t = c Y_t dt + \frac{h(X_t)}{\sqrt{T}} dt + \sigma dW_t, \quad X_0, \quad 0 \leq t \leq T.$$

Then $(r = (a^2 + b^2 c^2 \sigma^{-2})^{1/2})$

$$W_T^2 = \int_0^1 \left[W(s) + \frac{1}{\sigma T} \int_0^{sT} \left[1 - \frac{c^2}{\sigma^2} e^{-r(sT-v)} \right] h(X_v) dv \right]^2 ds$$

Limit=open question.

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